

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3441	702/182	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:02
L2	363	702/47	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:03
L3	3	wafer with ((stage) or (flatfom) or (staged) or (flatformed) or (staging)) with perpendicular with ((nozzle) or (nozzled) or (nozzles) or (nozzler) or (projecting) or (opening) or (opened) or (openned)) and valve and ((control) or (controlling) or (controller)) and ((pressure) or (pressurize) or (pressurizing) or (pressured)) and ((trigger) or (triggering) or (triggered) or (activate) or (activated) or (activating) or (indicating) or (indication) or (indicator) or (indicate) or (indicated))	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:03

L4	1	wafer with ((stage) or (flatfom) or (staged) or (flatformed) or (staging)) with perpendicular with ((nozzle) or (nozzled) or (nozzles) or (nozzler) or (projecting) or (openning) or (opened) or (openned)) and valve and ((control) or (controlling) or (controller)) and ((pressure) or (pressurize) or (pressurizing) or (pressured)) and ((trigger) or (triggering) or (triggered) or (activate) or (activated) or (activating) or (indicating) or (indication) or (indicator) or (indicate) or (indicated)).CLM.	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:12
L5	1	((halama with michael) or (kneh with albert) or (schmidt with guenter)) and wafer and ((stage) or (flatfom) or (staged) or (flatformed) or (staging)) and perpendicular and ((nozzle) or (nozzled) or (nozzles) or (nozzler) or (projecting)) and valve and ((control) or (controlling) or (controller)) and ((pressure) or (pressurize) or (pressurizing) or (pressured)) and ((trigger) or (triggering) or (triggered) or	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:19

		(activate) or (activated) or (activating))				
L6	2	"20010030739"	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:20
L7	14	((wafer adj inspection) or (wafer with inspecting)) and ((cushion) or (cushioned)) and nozzle and valve	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:23
L8	14	((wafer adj inspection) or (wafer with inspecting)) and ((cushion) or (cushioned)) and nozzle and valve and ((control) or (controller) or (controlling)) and pressure	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:23
L9	14	((wafer adj inspection) or (wafer with inspecting)) and ((cushion) or (cushioned)) and nozzle and valve and ((control) or (controller) or (controlling)) and pressure and perpendicular	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:24
L10	3	((wafer adj inspection) or (wafer with inspecting)) and ((cushion) or (cushioned)) and nozzle and valve and ((control) or (controller) or (controlling)) and pressure and perpendicular.CLM.	US-PGPUB; USPAT; EPO; DERWENT	OR	ON	2008/05/21 08:44

5/ 21/ 08 8:47:06 AM

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